

Docket No.: H6808.0024/P024
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Hiroshi Miyai, et al.

Application No.: Not Yet Assigned

Filed: Concurrently Herewith

Art Unit: N/A

For: EXAMINATION METHOD AND
APPARATUS USING ELECTRON BEAM

Examiner: Not Yet Assigned

CLAIM FOR PRIORITY

MS Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

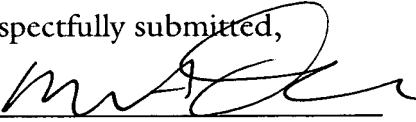
Applicant hereby claims priority under 35 U.S.C. 119 based on the following
prior foreign application filed in the following foreign country on the date indicated:

<u>Country</u>	<u>Application No.</u>	<u>Date</u>
Japan	2002-280142	September 26, 2002

In support of this claim, a certified copy of the said original foreign application will be filed shortly.

Dated: September 25, 2003

Respectfully submitted,

By 

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